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May 2008

FDB8896

N-Channel PowerTrench[®] MOSFET 30V, 93A, 5.7m Ω

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\mbox{\scriptsize DS(ON)}}$ and fast switching speed.

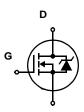
Applications

DC/DC converters

Features

- $r_{DS(ON)} = 5.7 m\Omega$, $V_{GS} = 10 V$, $I_D = 35 A$
- $r_{DS(ON)} = 6.8 \text{m}\Omega$, $V_{GS} = 4.5 \text{V}$, $I_D = 35 \text{A}$
- High performance trench technology for extremely low r_{DS(ON)}
- · Low gate charge
- · High power and current handling capability





MOSFET Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Ratings	Units V	
V_{DSS}	Drain to Source Voltage	30		
V _{GS}	Gate to Source Voltage	±20	V	
I _D	Drain Current			
	Continuous (T _C = 25°C, V _{GS} = 10V) (Note 1)	93	Α	
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 4.5V$) (Note 1)	85	А	
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 43^{\circ}C/W$)	19	А	
	Pulsed	Figure 4	А	
E _{AS}	Single Pulse Avalanche Energy (Note 2)	74	mJ	
P _D	Power dissipation	80	W	
	Derate above 25°C	0.53	W/°C	
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C	

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-263	1.88	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-263 (Note 3)	62	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-263, 1in ² copper pad area	43	°C/W

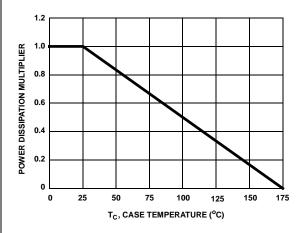
Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB8896	FDB8896	TO-263AB	330mm	24mm	800 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units	
Off Chara	cteristics						
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30	-	-	V	
I _{DSS}	Zara Cata Valtaga Drain Current	V _{DS} = 24V	-	-	1	μА	
	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ $T_C = 150^{\circ}C$	-	-	250		
I_{GSS}	Gate to Source Leakage Current	V _{GS} = ±20V	-	-	±100	nA	
On Chara	cteristics						
V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.2	-	2.5	V	
		I _D = 35A, V _{GS} = 10V	-	0.0049	0.0057		
r	Drain to Source On Resistance	I _D = 35A, V _{GS} = 4.5V	-	0.0059	0.0068		
r _{DS(ON)}	Drain to Source On Resistance	$I_D = 35A, V_{GS} = 10V,$ $T_J = 175^{\circ}C$	-	0.0078	0.0094	Δ	
Dynamic	Characteristics						
C _{ISS}	Input Capacitance		-	2525	-	pF	
C _{OSS}	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$	-	490	-	pF	
C _{RSS}	Reverse Transfer Capacitance	f = 1MHz	-	300	-	pF	
R _G	Gate Resistance	V _{GS} = 0.5V, f = 1MHz	-	2.3	-	Ω	
Q _{g(TOT)}	Total Gate Charge at 10V	V _{GS} = 0V to 10V	-	48	67	nC	
Q _{g(5)}	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$	-	25	36	nC	
Q _{q(TH)}	Threshold Gate Charge	$V_{DD} = 15V$	-	2.3	3.0	nC	
Q _{qs}	Gate to Source Gate Charge	$I_D = 35A$ $I_a = 1.0 \text{mA}$	-	8	-	nC	
Q _{gs2}	Gate Charge Threshold to Plateau		-	5.7	-	nC	
Q _{gd}	Gate to Drain "Miller" Charge		-	9.5	-	nC	
Switching	Characteristics (V _{GS} = 10V)						
t _{ON}	Turn-On Time		-	-	167	ns	
t _{d(ON)}	Turn-On Delay Time	7	-	9	-	ns	
t _r	Rise Time	V _{DD} = 15V, I _D = 35A	-	102	-	ns	
t _{d(OFF)}	Turn-Off Delay Time	$V_{GS} = 4.5V, R_{GS} = 6.2\Omega$	-	58	-	ns	
t _f	Fall Time	7	-	44	-	ns	
t _{OFF}	Turn-Off Time	7	-	-	153	ns	
Drain-Sou	urce Diode Characteristics						
		I _{SD} = 35A	-	-	1.25	V	
V_{SD}	Source to Drain Diode Voltage	I _{SD} = 20A	-	-	1.0	V	
t _{rr}	Reverse Recovery Time	$I_{SD} = 35A$, $dI_{SD}/dt = 100A/\mu s$	-	-	27	ns	
Q _{RR}	Reverse Recovered Charge	$I_{SD} = 35A$, $dI_{SD}/dt = 100A/\mu s$	_	_	12	nC	

- Notes: 1: Package current limitation is 80A. 2: Starting $T_J = 25^{\circ}C$, $L = 36\mu H$, $I_{AS} = 64A$, $V_{DD} = 27V$, $V_{GS} = 10V$. 3: Pulse width = 100s.





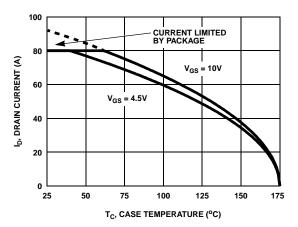


Figure 1. Normalized Power Dissipation vs Case Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature

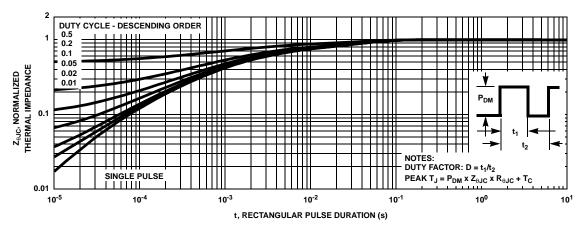


Figure 3. Normalized Maximum Transient Thermal Impedance

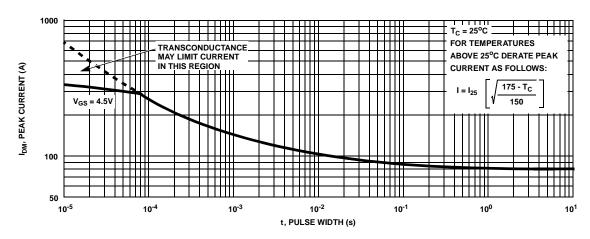
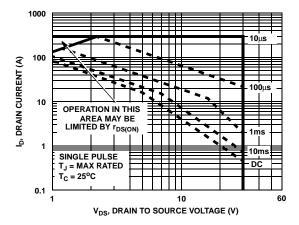


Figure 4. Peak Current Capability

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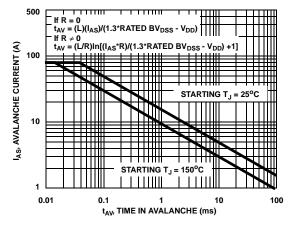
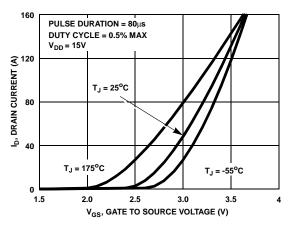


Figure 5. Forward Bias Safe Operating Area

NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching

Capability



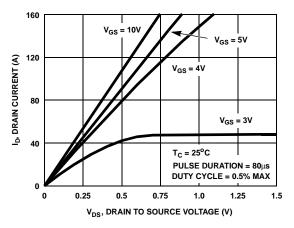
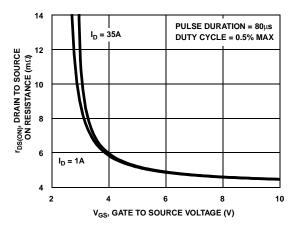


Figure 7. Transfer Characteristics

Figure 8. Saturation Characteristics



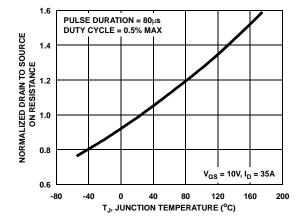


Figure 9. Drain to Source On Resistance vs Gate Voltage and Drain Current

Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

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Typical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

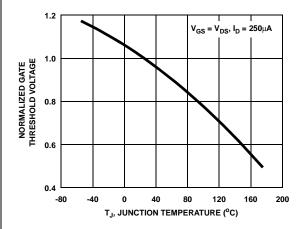


Figure 11. Normalized Gate Threshold Voltage vs
Junction Temperature

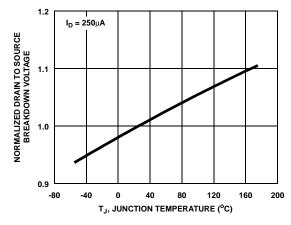


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

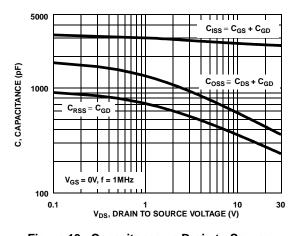


Figure 13. Capacitance vs Drain to Source Voltage

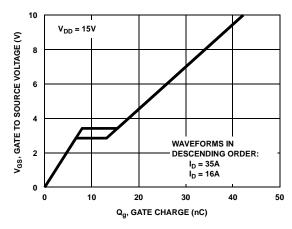


Figure 14. Gate Charge Waveforms for Constant Gate Current

Test Circuits and Waveforms

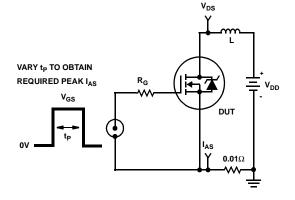


Figure 15. Unclamped Energy Test Circuit

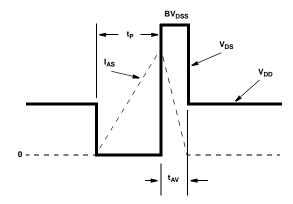


Figure 16. Unclamped Energy Waveforms

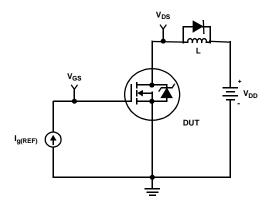


Figure 17. Gate Charge Test Circuit

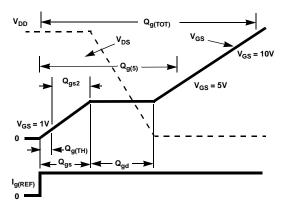


Figure 18. Gate Charge Waveforms

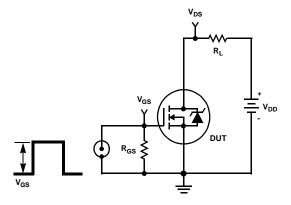


Figure 19. Switching Time Test Circuit

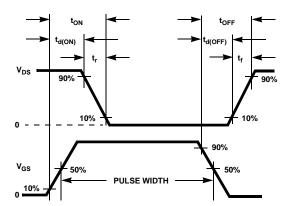


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \tag{EQ. 1}$$

In using surface mount devices such as the TO-263 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 26.51 + \frac{19.84}{(0.262 + Area)}$$
 (EQ. 2)

Area in Inches Squared

$$R_{\theta JA} = 26.51 + \frac{128}{(1.69 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

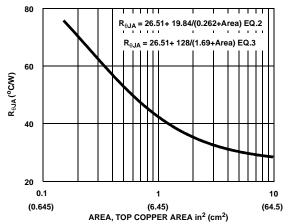
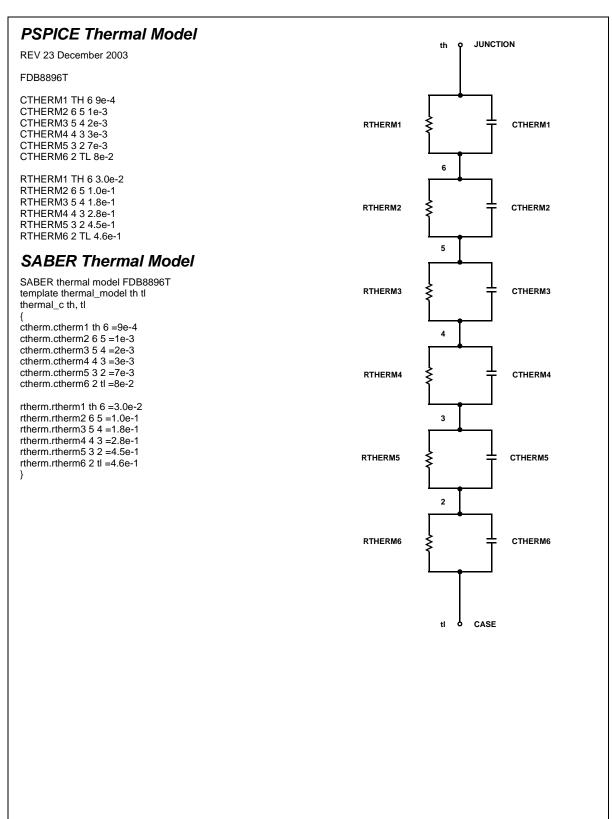


Figure 21. Thermal Resistance vs Mounting
Pad Area

PSPICE Electrical Model .SUBCKT FDB8896 2 1 3 ; rev December 2003 Ca 12 8 2 3e-9 LDRAIN DPLCAP DRAIN Cb 15 14 2.3e-9 Cin 6 8 2.3e-9 10 RLDRAIN RSLC1 Dbody 7 5 DbodyMOD DBREAK Dbreak 5 11 DbreakMOD RSLC2 § Dplcap 10 5 DplcapMOD FSI C 11 50 Ebreak 11 7 17 18 33 Eds 14 8 5 8 1 ■ DBODY RDRAIN **EBREAK ESG** Eas 13 8 6 8 1 **FVTHRES** Esg 6 10 6 8 1 $\left(\frac{19}{8}\right)$ MWFAK Evthres 6 21 19 8 1 LGATE **EVTEMP** Evtemp 20 6 18 22 1 GATE **RGATE** (18 22 匤 MMFD 9 20 MSTRO It 8 17 1 RIGATE LSOURCE CIN SOURCE Lgate 1 9 5.5e-9 Ldrain 2 5 1.0e-9 RSOURCE I source 3 7 2.7e-9 RLSOURCE RBREAK RLgate 1 9 55 13 8 18 RLdrain 2 5 10 RLsource 3 7 27 RVTEMP S1B o S2B СВ 19 CA Mmed 16 6 8 8 MmedMOD IT 14 Mstro 16 6 8 8 MstroMOD VBAT EGS Mweak 16 21 8 8 MweakMOD 8 Rbreak 17 18 RbreakMOD 1 **RVTHRES** Rdrain 50 16 RdrainMOD 2.1e-3 Rgate 9 20 2.3 RŠLC1 5 51 RSLCMOD 1e-6 RSLC2 5 50 1e3 Rsource 8 7 RsourceMOD 2e-3 Rvthres 22 8 RvthresMOD 1 Rvtemp 18 19 RvtempMOD 1 S1a 6 12 13 8 S1AMOD S1b 13 12 13 8 S1BMOD S2a 6 15 14 13 S2AMOD S2b 13 15 14 13 S2BMOD Vbat 22 19 DC 1 ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*500),10))} .MODEL DbodyMOD D (IS=4E-12 IKF=10 N=1.01 RS=2.6e-3 TRS1=8e-4 TRS2=2e-7 + CJO=8.8e-10 M=0.57 TT=1e-16 XTI=2.2) .MODEL DbreakMOD D (RS=8e-2 TRS1=1e-3 TRS2=-8.9e-6) .MODEL DplcapMOD D (CJO=9.4e-10 IS=1e-30 N=10 M=0.4) .MODEL MmedMOD NMOS (VTO=1.98 KP=10 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=2.3 T ABS=25) .MODEL MstroMOD NMOS (VTO=2.4 KP=350 IS=1e-30 N=10 TOX=1 L=1u W=1u T_ABS=25) .MODEL MweakMOD NMOS (VTO=1.68 KP=0.05 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=23 RS=0.1 T_ABS=25) .MODEL RbreakMOD RES (TC1=8.3e-4 TC2=-4e-7) .MODEL RdrainMOD RES (TC1=1.2e-3 TC2=8e-6) MODEL RSLCMOD RES (TC1=9e-4 TC2=1e-6) .MODEL RsourceMOD RES (TC1=7.5e-3 TC2=1e-6) .MODEL RvthresMOD RES (TC1=-2.4e-3 TC2=-8.8e-6) .MODEL RvtempMOD RES (TC1=-2.6e-3 TC2=2e-7) .MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-4 VOFF=-3) .MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-3 VOFF=-4) .MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2 VOFF=-0.5) .MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-0.5 VOFF=-2) **FNDS** Note: For further discussion of the PSPICE model, consult A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

SABER Electrical Model rev December 2003 template FDB8896 n2,n1,n3 =m temp electrical n2,n1,n3 number m_temp=25 var i iscl $dp..model\ dbodymod = \ (isl=4e-12,ikf=10,nl=1.01,rs=2.6e-3,trs1=8e-4,trs2=2e-7,cjo=8.8e-10,m=0.57,tt=1e-16,xti=2.2)$ dp..model dbreakmod = (rs=8e-2,trs1=1e-3,trs2=-8.9e-6) dp..model dplcapmod = (cjo=9.4e-10,isl=10e-30,nl=10,m=0.4) m..model mmedmod = $(type=_n, vto=1.98, kp=10, is=1e-30, tox=1)$ m..model mstrongmod = (type= n, vto=2.4, kp=350, is=1e-30, tox=1)m..model mweakmod = (type=_n,vto=1.68,kp=0.05,is=1e-30, tox=1,rs=0.1) LDRAIN sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-4,voff=-3) **DPLCAP** DRAIN sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-3,voff=-4) 10 sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-2,voff=-0.5) RLDRAIN sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-0.5,voff=-2) RSLC1 c.ca n12 n8 = 2.3e-951 RSLC2 € c.cb n15 n14 = 2.3e-9ISCI c.cin n6 n8 = 2.3e-9DBREAK dp.dbody n7 n5 = model=dbodymod RDRAIN <u>6</u>8 dp.dbreak n5 n11 = model=dbreakmod **FSG** DBODY dp.dplcap n10 n5 = model=dplcapmod **EVTHRES** (<u>19</u>) **MWEAK** LGATE **EVTEMP** spe.ebreak n11 n7 n17 n18 = 33 GATE **ММ**ЕД 18 22 EBREAK spe.eds n14 n8 n5 n8 = 1 spe.egs n13 n8 n6 n8 = 1 **←**MSTRC RLGATE spe.esg n6 n10 n6 n8 = 1 LSOURCE spe.evthres n6 n21 n19 n8 = 1 CIN SOURCE spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RLSOURCE i.it n8 n17 = 1 RBREAK I.lgate n1 n9 = 5.5e-9I.Idrain n2 n5 = 1.0e-9**₹**RVTEMP S1B oS2B I.Isource n3 n7 = 2.7e-919 СА IT (♠ 14 res.rlgate n1 n9 = 55 VBAT res.rldrain n2 n5 = 10 **EGS EDS** res.rlsource n3 n7 = 27 m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u, temp=m_temp **RVTHRES** m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u, temp=m_temp m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u, temp=m_temp res.rbreak n17 n18 = 1, tc1=8.3e-4,tc2=-4e-7 res.rdrain n50 n16 = 2.1e-3, tc1=1.2e-3,tc2=8e-6 res.rgate n9 n20 = 2.3res.rslc1 n5 n51 = 1e-6, tc1=9e-4,tc2=1e-6 res.rslc2 n5 n50 = 1e3res.rsource n8 n7 = 2e-3, tc1=7.5e-3,tc2=1e-6 res.rvthres n22 n8 = 1, tc1=-2.4e-3, tc2=-8.8e-6res.rvtemp n18 n19 = 1. tc1=-2.6e-3.tc2=2e-7sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/500))** 10))

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 (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
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Preliminary	First Production	This datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
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